

IN THE CLAIMS:

Please amend the claims as follows.

1. (Currently Amended) A testing apparatus having a plurality of testing module slots onto which different types of testing modules for generating different types of test signals to test a device under test are optionally selectively mounted, comprising:  
a plurality of controlling modules for supplying [[a]] control signals to each of said testing modules, ~~said testing modules being~~ mounted on said testing module slots ~~respectively~~, said control signals being used for controlling said testing modules;  
setting information supplying means for supplying hardware setting information to a specific testing module among said testing modules, said hardware setting information being set in advance in said controlling module ~~in order to send~~ ~~said control signal in response corresponding~~ to said specific testing module;  
enable signal controlling means for instructing said specific testing module to generate and supply an enable signal to said controlling module ~~supplying~~ ~~said control signal corresponding~~ to said specific testing module; and  
setting means for setting ~~a specific~~ ~~said~~ controlling module ~~received said enable signal from said specific testing module of said controlling modules so as to~~ supply said control signal ~~in response corresponding~~ to said specific testing module to said specific testing module based on said hardware setting information, ~~said specific controlling module receiving said enable signal from said specific testing module.~~

2. (Currently Amended) A testing apparatus as claimed in claim 1, wherein at least one of said plurality of controlling modules comprises a plurality of interfaces for inputting different types of said control signals respectively, said setting information supplying means selects a specific control signal among said control signals and supplies said hardware setting information to said controlling module corresponding to said specific testing module via a specific interface among said interfaces, said specific interface inputting that inputs said specific control signal to said controlling module, and said setting means sets said controlling module received said enable signal from said specific testing module so as to supply said specific control signal to said specific testing module, said specific control signal being inputted from said specific interface to said controlling module.

3. (Currently Amended) A testing apparatus as claimed in claim 2, wherein the at least one of said plurality of controlling module further comprises: a multiplexer circuit for selecting said specific control signal to be supplied to said specific testing module among said control signals inputted from said interfaces respectively; and a flip-flop circuit for holding information indicating that said hardware setting information is inputted from said specific interface as a select signal for controlling said multiplexer circuit to select said specific control signal, based on a setting request signal supplied from said setting means, when

said enable signal is received from said specific testing module.

4. (Currently Amended) A testing apparatus as claimed in claim 3, wherein said control signals ~~is-a~~ are trigger signals for controlling said testing modules, and said multiplexer circuit selects and supplies a specific trigger signal to be supplied to said specific testing module among different types of said trigger signals inputted from said interfaces respectively.
5. (Currently Amended) A testing apparatus as claimed in claim 3, wherein said control signals ~~is-a~~ are clock signals for controlling said testing modules, and said multiplexer circuit selects and supplies a specific clock signal to be supplied to said specific testing module among different types of said clock signals inputted from said interfaces respectively.
6. (Currently Amended) A testing apparatus as claimed in claim 2, wherein the at least one of said plurality of controlling modules further comprises:  
    a first multiplexer circuit for selecting a specific trigger signal to be supplied to said specific testing module among different types of trigger signals for controlling said testing modules, said trigger signals being inputted from each of said interfaces as said control signals;  
    a first flip-flop circuit for holding information indicating that said hardware setting information is inputted from said specific interface as a select signal for controlling said first multiplexer circuit to select said specific trigger signal,

based on a setting request signal supplied from said setting means, when said enable signal is received from said specific testing module;

a second multiplexer circuit for selecting a specific clock signal to be supplied to said specific testing module among different types of clock signals for controlling said testing modules, said clock signals being inputted from each of said interfaces as said control signals; and

a second flip-flop circuit for holding information indicating that said hardware setting information is inputted from said specific interface as a select signal for controlling said second multiplexer circuit to select said specific clock signal, based on a setting request signal supplied from said setting means, when said enable signal is received from said specific testing module.

7. (Currently Amended) A testing apparatus as claimed in claim 2, further comprising:

a first site controlling apparatus for controlling a first testing module among said testing modules; and

a second site controlling apparatus for controlling a second testing module among said testing modules,

wherein said enable signal controlling means instructs said first testing module to generate and supply said enable signal to a first controlling module corresponding to said first testing module among said controlling modules, said first controlling module supplying said control signal to said first testing module, and said second testing module to generate and supply said enable signal to a second controlling module corresponding to said second

~~testing module among said controlling modules, said second controlling module supplying said control signal to said second testing module,~~  
said setting information supplying means supplies said hardware setting information via a first interface among said interfaces, ~~said first interface inputting that inputs said a first~~ control signal generated under [[the]] control of said first site controlling apparatus to said first controlling module, and via a second interface among said interfaces, ~~said second interface inputting that inputs said a second~~ control signal generated under [[the]] control of said second site controlling apparatus to said second controlling module, and  
said setting means sets said first controlling module so as to supply said first control signal to said first testing module, said first control signal being inputted from said first interface to said first controlling module, and sets said second controlling module so as to supply said second control signal to said second testing module, said second control signal being inputted from said second interface to said second controlling module.

8. (Currently Amended) A testing apparatus as claimed in claim 2, wherein said testing apparatus tests a plurality of said devices under test substantially concurrently at the same time,  
said enable signal controlling means instructs a first testing module among said testing modules to generate and supply said enable signal to a first controlling module among said controlling modules, said first testing

module supplying said test signal to a first device under test among said devices under test, said first controlling module supplying said control signal to said first testing module, and a second testing module among said testing modules to generate and supply said enable signal to a second controlling module among said controlling modules, said second testing module supplying said test signal to a second device under test among said devices under test, said second controlling module supplying said control signal to said second testing module,

said setting information supplying means supplies said hardware setting information via a first interface among said interfaces, said first interface inputting said-a first control signal for controlling [[the]]a test of said first device under test to said first controlling module, and via a second interface among said interfaces, said second interface inputting said-a second control signal for controlling [[the]]a test of said second device under test to said second controlling module, and

said setting means sets said first controlling module so as to supply said first control signal to said first testing module, said first control signal being inputted from said first interface to said first controlling module, and said second controlling module so as to supply said second control signal to said second testing module, said second control signal being inputted from said second interface to said second controlling module.

9. (Currently Amended) A testing apparatus as claimed in claim 1, wherein said testing

modules are analog measuring modules for performing an analog test of said device under test, and

    said controlling modules supply [[a]]said control signals to each of said analog measuring modules, said control signals being used for controlling said analog measuring modules.